Intrusion, Malware Detection and Prevention in 5G Networks and Internet of Things

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Message from the Guest Editors

Fifth-generation networks are rapidly spreading across the world, enabling connection between millions of devices in consumer and industrial IoT applications. The 5G evolution has introduced new models for network architectures and improved physical data rates, supporting a high number of connected devices and enabling new ecosystems for the deployment of novel services and applications.

This Special Issue aims to represent the latest advances in malware, intrusion detection, and prevention, encompassing application scenarios such as (and not limited to):

- Mechanisms for data collection and processing leveraging edge computing models for the security of IoT applications;
- Algorithms and techniques for malware detection in IoT applications and mobile devices;
- Algorithms and techniques for intrusion detection and protection in 5G services.

Special Issue

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Message from the Editor-in-Chief

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